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Application/Control No.	Applicant(s)/Patent under Reexamination
10/621,447	KWON ET AL.
Examiner	Art Unit

2611

Leila Malek

SEARCHED				
Class	Subclass	Date	Examiner	
375	150	3/9/2007	L.M	
455	63.1	3/9/2007	L.M	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST	3/9/2007	L.M	
IEEE	3/9/2007	L.M	
GOOGLE	3/9/2007	L.M	
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